

# **Test of the Silicon Detectors**



### **Detector Properties**

#### **CERBEROS** (Central Beam tracker for pions)

#### Silicon detector



Micron Semiconductor Inc.

10x10 cm<sup>2</sup> - size 2x128 channels – double sided 300 μm thick n<sup>+</sup>-p junction type – radiation hardness

### **Test Setup**





Setup 2: Readout Strip 33-64 / 65-128

Analog for backside of detector

# Leakage Current

#### Leckeage Current



• 2814 – 24 : used in Julich test - Beamtime

# **Calibration procedure**

Shown for an example Readout Position 0 = (0-31,64-95) n- side of detector

#### **Noise Behavior**



### **Noise Behavior**



## Test with triple alpha source

Pu(239)

Am(241)

Cu(244)



## Calibration



ADC value = **A** + **B**\*Energy

```
<u>Calibration:</u>
Energy of Channel = (ADC value - A)/B
```

### **Noise calibrated**



## triple alpha calibrated



### triple alpha calibrated



### triple alpha calibrated



# **Result summary**

#### **n-Side of Detector**



#### **n-Side of Detector**



#### **p-Side of Detector**



### **p-Side of Detector**



# **Summary & Outlook**

#### **Test of Detector 1:**

- Leakage Current Stable: Higher value due to different bias resistor
- 100% of strips are working well
- Energy resolution: <1 % @ 5 MeV
- Noise: ~2500 e- (Preamplifier)

#### Outlook

- Continue tests with detector 2 and 3
- Tests with beta-Source (Separation Noise/Signal)

# Backup

### Test with triple alpha source



ADC Value



#### **Noise Behavior**

#### Fitted with a Gauss function



## Test with triple alpha source



### **Noise calibrated**



## **Noise calibrated**



Noise peak not at 0 after calibration still preliminary

# Besonderheiten

#### **p-Side of Detector**



### **p-Side of Detector**



Noise mean Energy [keV] -500 **Detector channel** Noise width [keV] 0 **Detector channel** 

Kalibration funktioniert hier viel besser !!





#### Alpha peaks sehen alle ganz gut aus bis auf Kanal 47!





